

Notice of References Cited	Application/Control No. 10/593,021		Applicant(s)/Patent Under Reexamination SCHMITT ET AL.	
	Examiner BACH T. DINH		Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0019279	01-2003	Scheer et al.	73/23.31
*	B	US-2002/0017462	02-2002	Diehl, Lothar	204/426
*	C	US-2004/0040847	03-2004	Suzuki, Kazunori	204/426
*	D	US-5,436,216	07-1995	Toyao et al.	502/439
*	E	US-2003/0230484	12-2003	Jain et al.	204/424
*	F	US-7,445,699	11-2008	Scheer et al.	204/425
*	G	US-2004/0140212	07-2004	Saguchi et al.	204/424
*	H	US-4,915,814	04-1990	Harada et al.	204/425
*	I	US-2001/0008211	07-2001	KATO et al.	204/426
*	J	US-2002/0017461	02-2002	Kunimoto et al.	204/424
*	K	US-2002/0108856	08-2002	Kunimoto et al.	204/425
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO03/036281	05-2003	JP	Scheer	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.